

# Inelastic x-ray scattering

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# Outline - I

## 1) Introduction

scattering kinematics

generic excitation spectrum & information content

some instrumental aspects

## 2) Resonant IXS

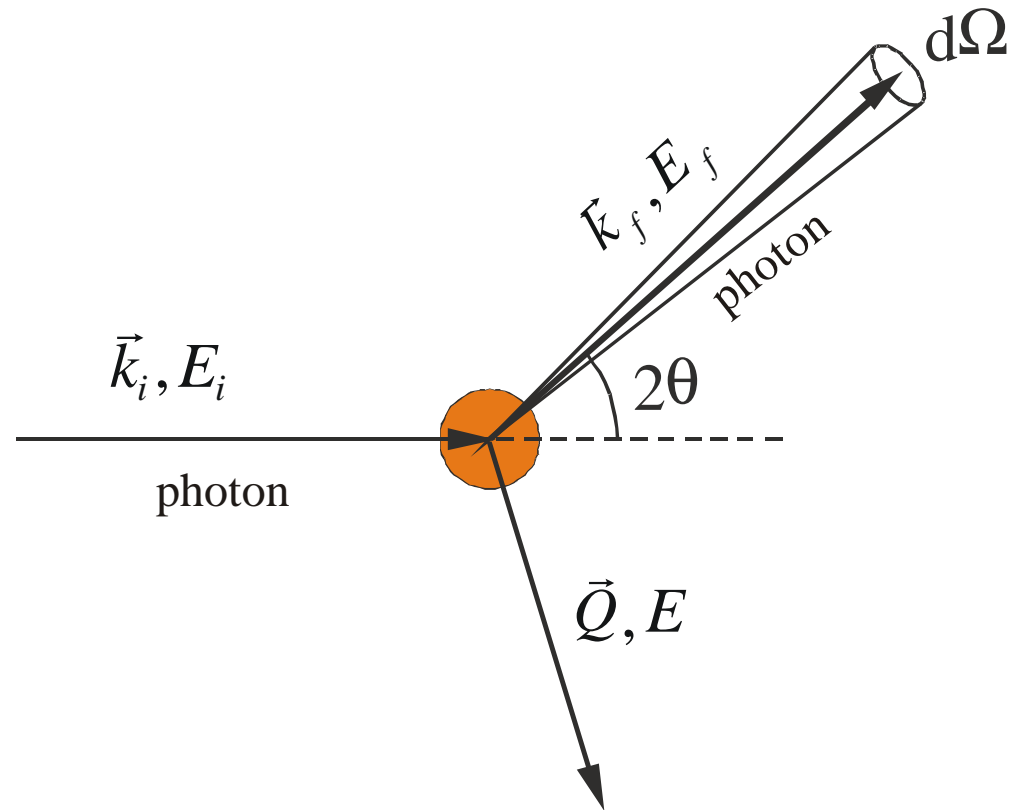
“XAS beyond the core hole lifetime broadening”

## 3) X-ray Raman scattering

“Soft x-ray XAS in the hard x-ray range”

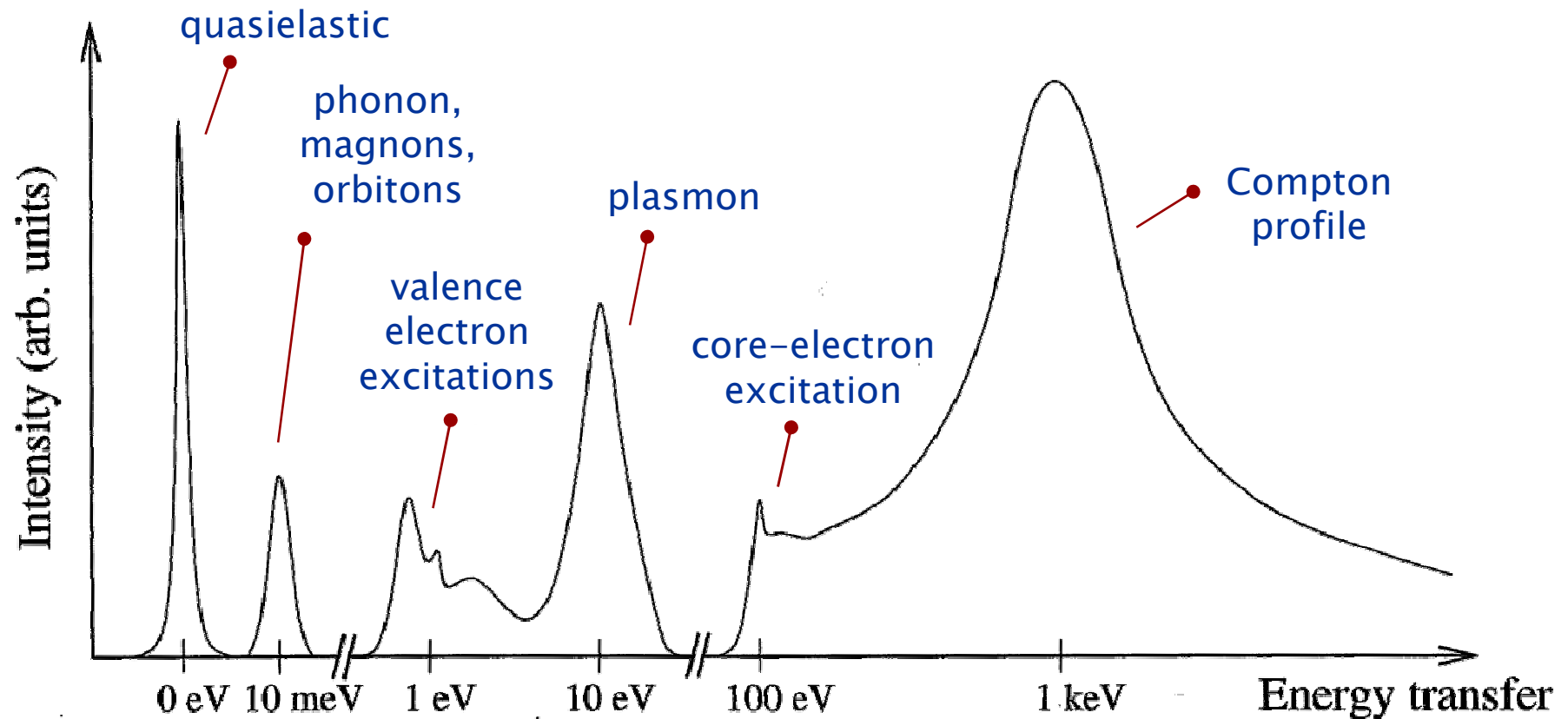
## 4) IXS – phonons

# Introduction I – scattering kinematics



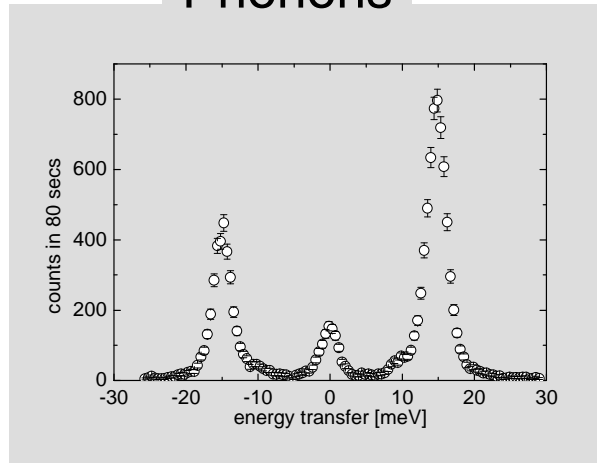
- Energy transfer:  $E_f - E_i = \Delta E = 1 \text{ meV} - \text{several keV}$
- Momentum transfer:  $\vec{k}_f - \vec{k}_i = \vec{Q} = 1 - 180 \text{ nm}^{-1}$

# Introduction II - schematic IXS spectrum



# Introduction III – overview 1

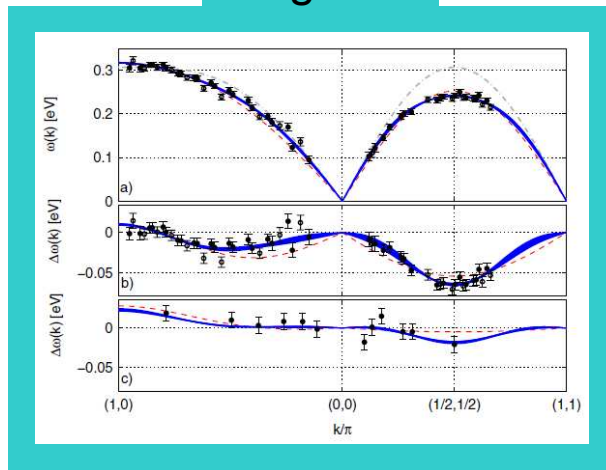
## Phonons



## Lattice dynamics

- elasticity
- thermodynamics
- phase stability
- e-ph coupling

## Magnons

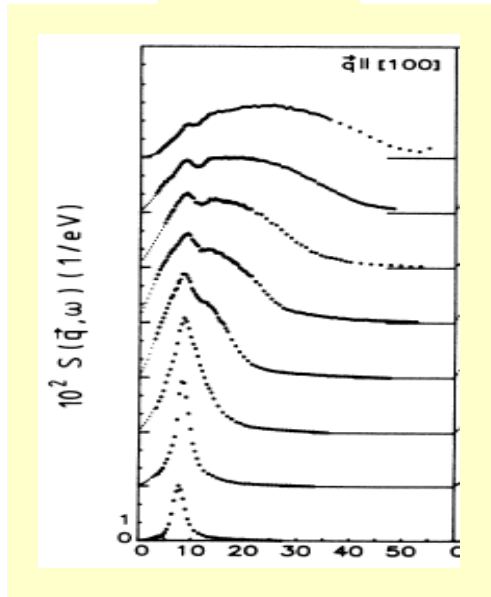


## Spin dynamics

- magnon dispersions
- exchange interactions

# Introduction IV – overview 2

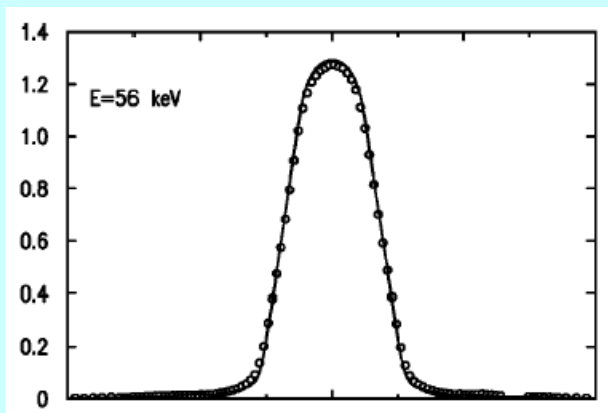
$S(Q, \omega)$



**Electron dynamics  $\epsilon(q, \omega)$**

- plasmons
- excitons
- orbitons

Compton scattering

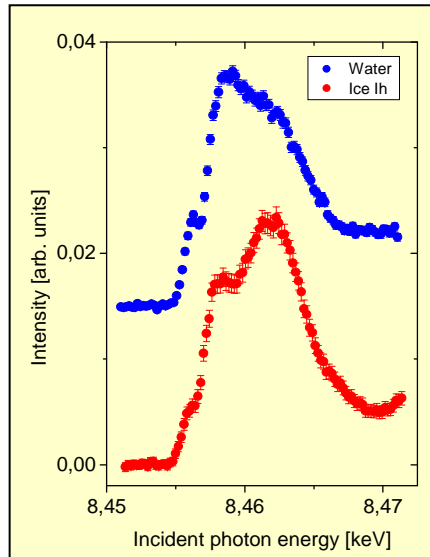


**Impulse distribution of electrons**

- chemical bonding
- local structures

# Introduction V – overview 3

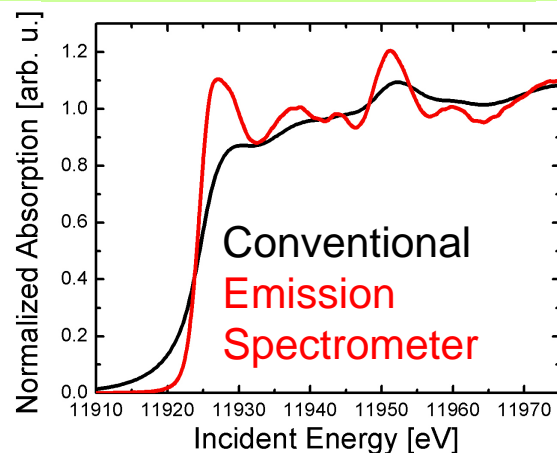
## X-ray Raman scattering



## IXS from core electrons

- electronic structure
- bulk sensitivity for low Z materials
- access to final states beyond the dipole limit

## RRS, HERFD XAS, ..

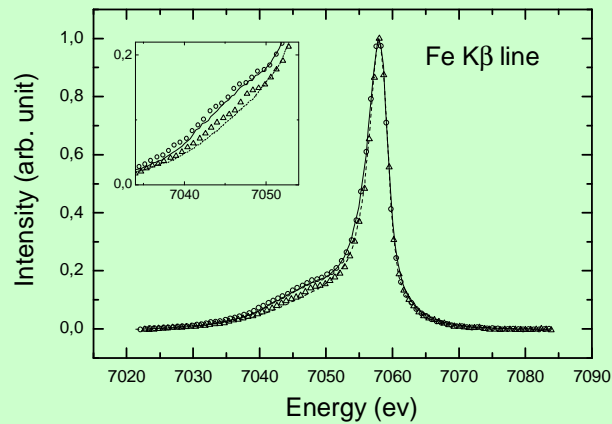


## Resonant IXS from core electrons

- electronic structure
- reduced life time broadening

# Introduction VI – overview 4

## X-ray emission



## X-ray emission/fluorescence

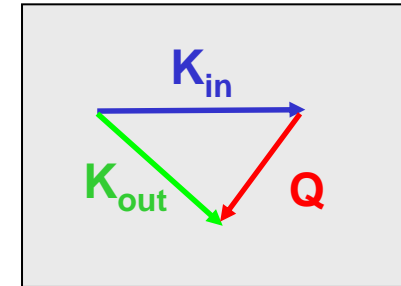
- element selective
- valence selective
- spin selective
- ligand selective



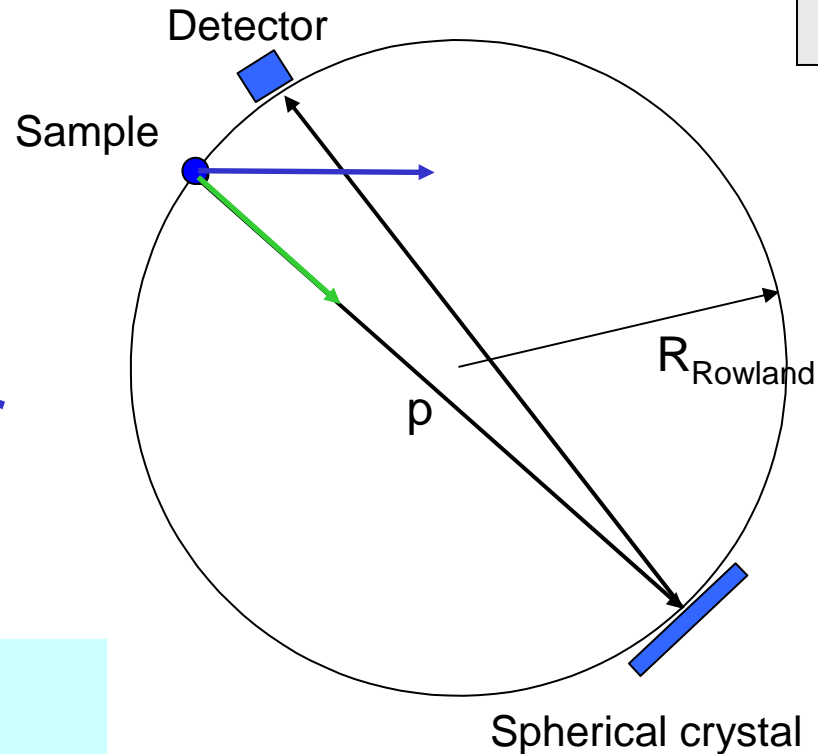
# Introduction VII – IXS instrumentation

## Energy analysis of scattered X-rays

- $\Delta E/E = 10^{-4} - 10^{-8}$
- some solid angle



## Rowland circle crystal spectrometer



$$p = R_{crystal} \cdot \sin\theta_B$$

$$R_{crys} = 2 \cdot R_{Rowl}$$



# Introduction VIII – IXS at the ESRF

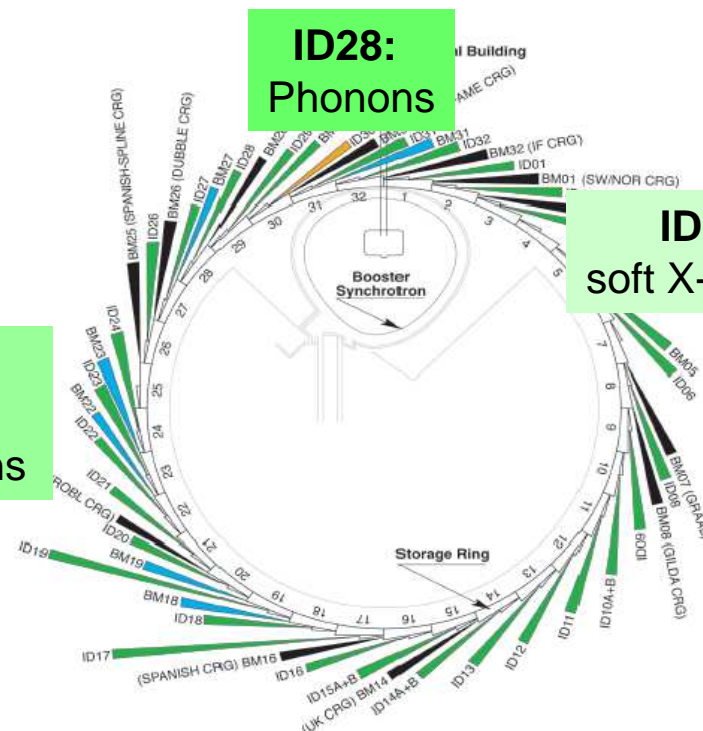


**ID26:**  
XAS and emission spectroscopy

**ID28:**  
Phonons

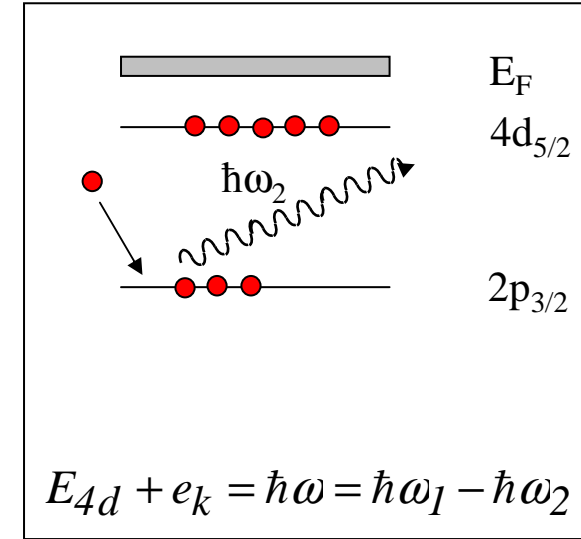
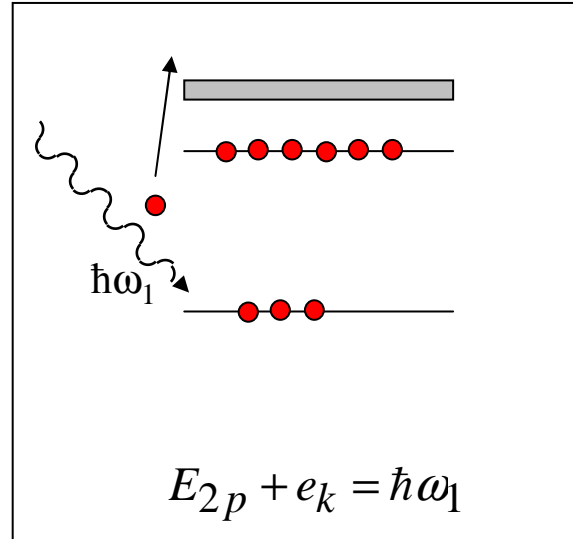
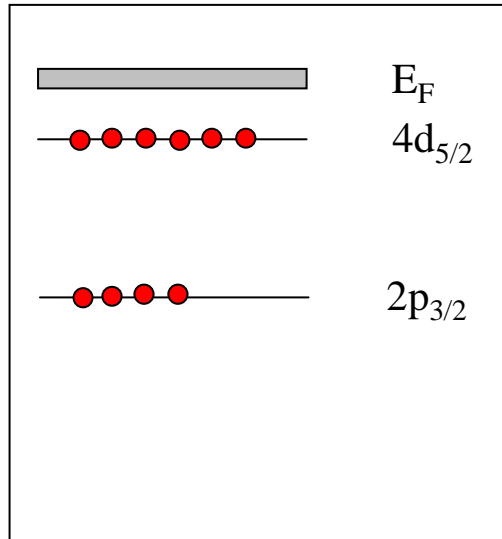
**ID32:**  
soft X-ray IXS

**ID20:**  
Electronic and  
magnetic excitations



**ID15B:**  
Compton: 30%

# Resonant IXS from core electrons - I

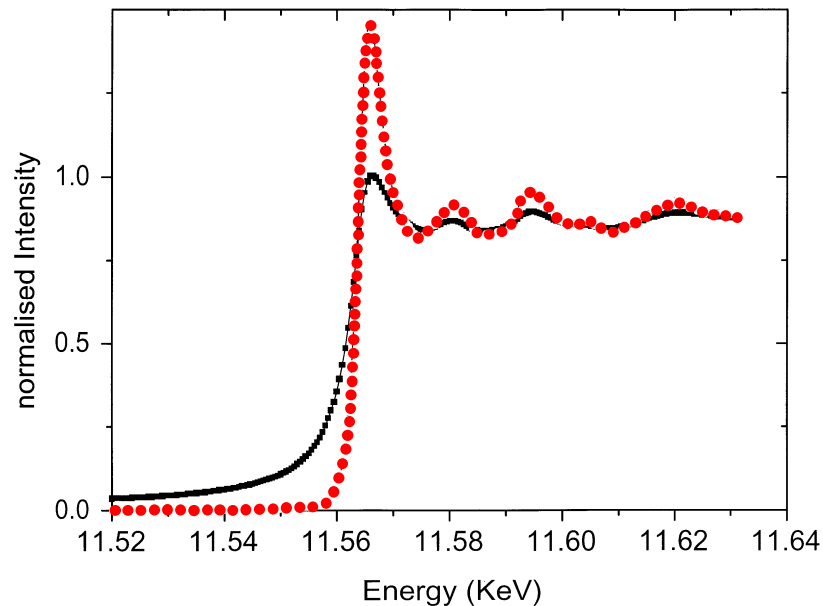


- Incident photon energy is tuned through the  $2p_{3/2}$  edge.
- The radiative decay channel, following the filling of the  $2p_{3/2}$  core hole, is monitored.

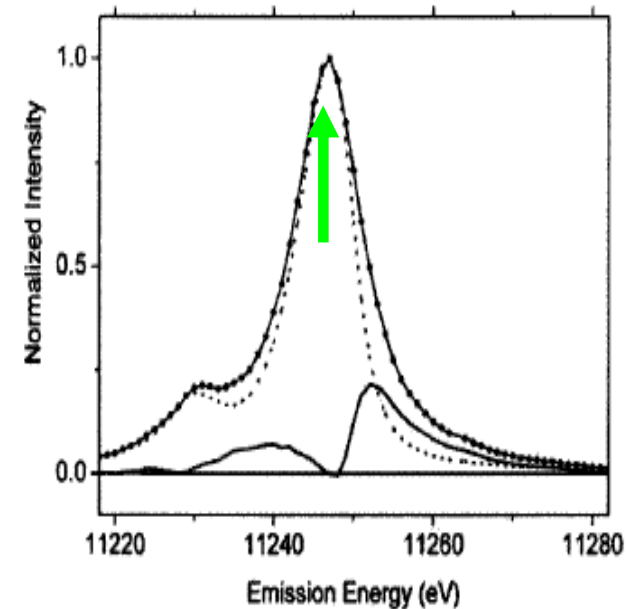
# Resonant IXS from core electrons - II

## “XAS beyond the core hole lifetime broadening”

XAS and **PFY/HERFD XAS**  
Pt metal  $L_3$  edge



Pt  $L\beta_2$  emission line  
 $4d \rightarrow 2p_{3/2}$



- $E_{\text{scatt}}$  fixed,  $E_{\text{inc}}$  tuned through absorption edge.
- Spectral sharpening by energy selection of emission channel.

# Resonant IXS from core electrons - II

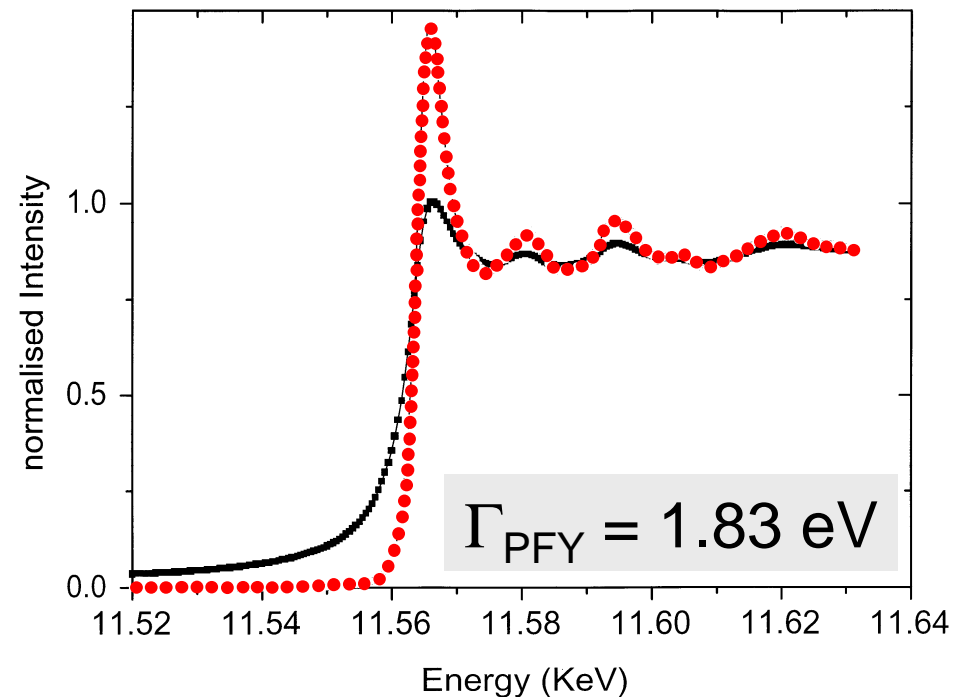
## Partial Fluorescence Yield X-ray Absorption Spectroscopy or High Energy Resolution Fluorescence Detected XAS

$$1/\Gamma_{PFY} = \sqrt{1/\Gamma_{2p}^2 + 1/\Gamma_{4d}^2}$$

**Pt L<sub>3</sub>-edge**

$$\Gamma_{L3} = 7 \text{ eV}$$

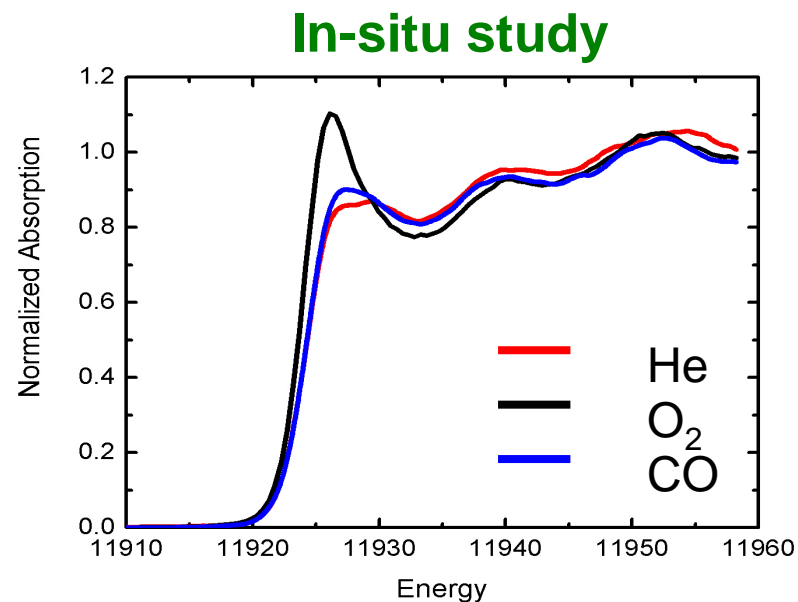
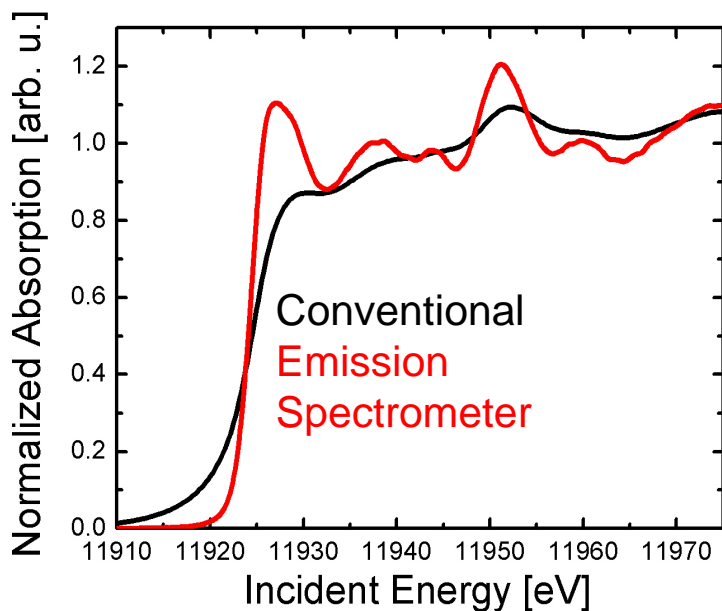
$$\Gamma_{M4,5} = 1.9 \text{ eV}$$



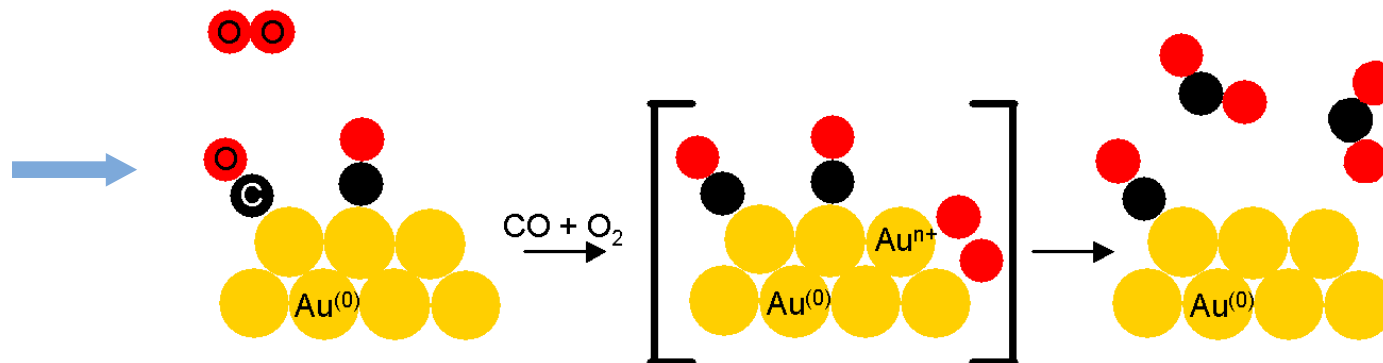
**Significant spectral sharpening !!!**

# RIXS from core electrons– Applications 1

## CO oxidation over gold nano-particles by high energy resolution XANES

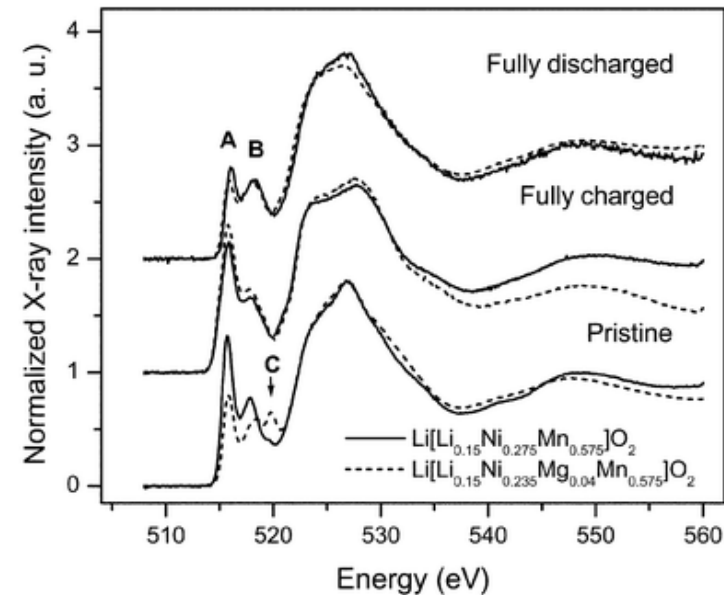
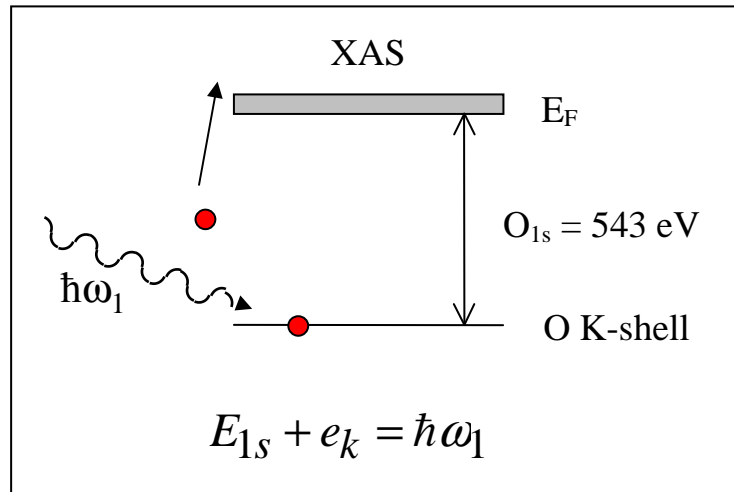


Reaction mechanism



# X-ray Raman scattering - I

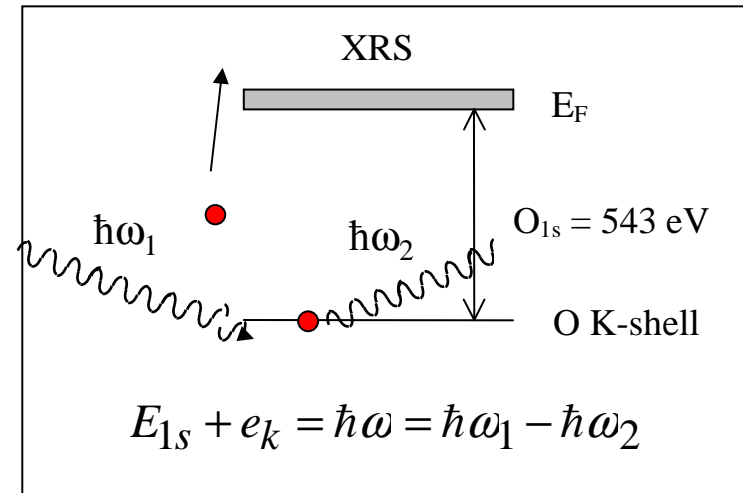
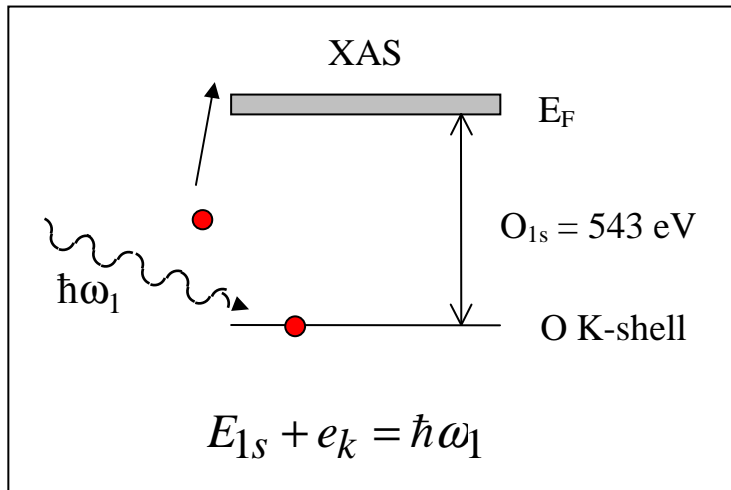
## X-ray absorption spectroscopy



Incident photon energy is tuned through the oxygen K-edge

Soft X-rays  $\Rightarrow$  (U)HV environment, surface sensitivity (?), experimental constraints

# X-ray Raman scattering - II



Role of incident photon energy in XAS is played by  
the energy transfer in XRS

=>

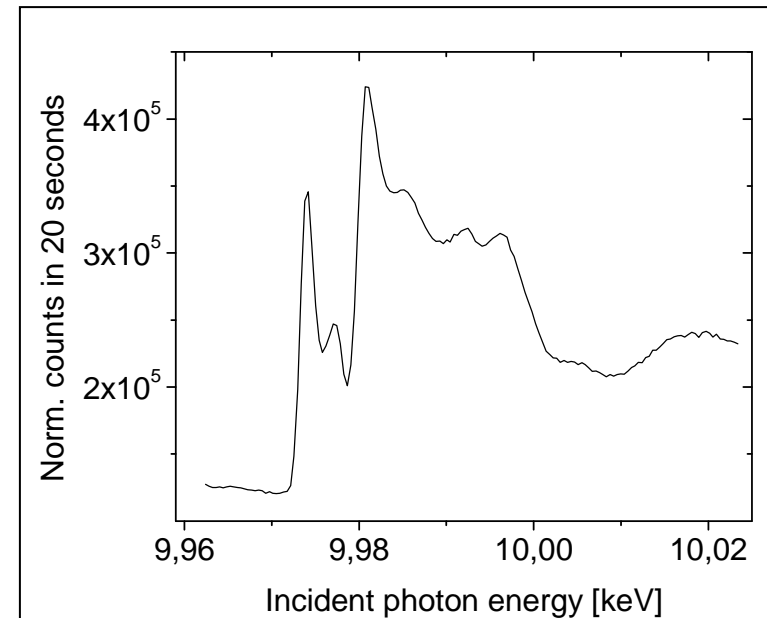
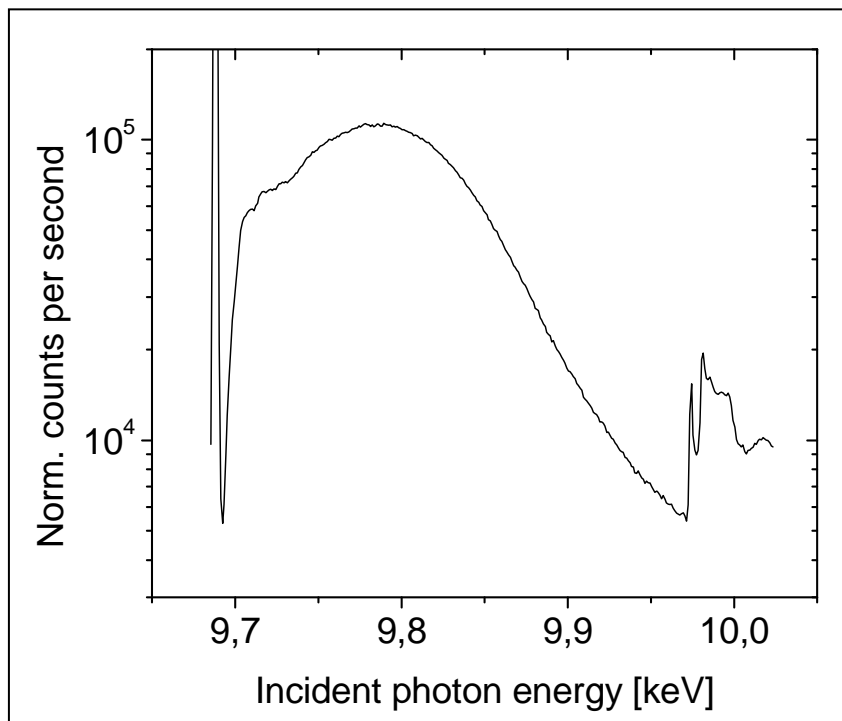
certain freedom in the choice of the incident photon energy

Hard X-rays => Bulk sensitivity; Access to buried layers  
High pressure and/or temperature



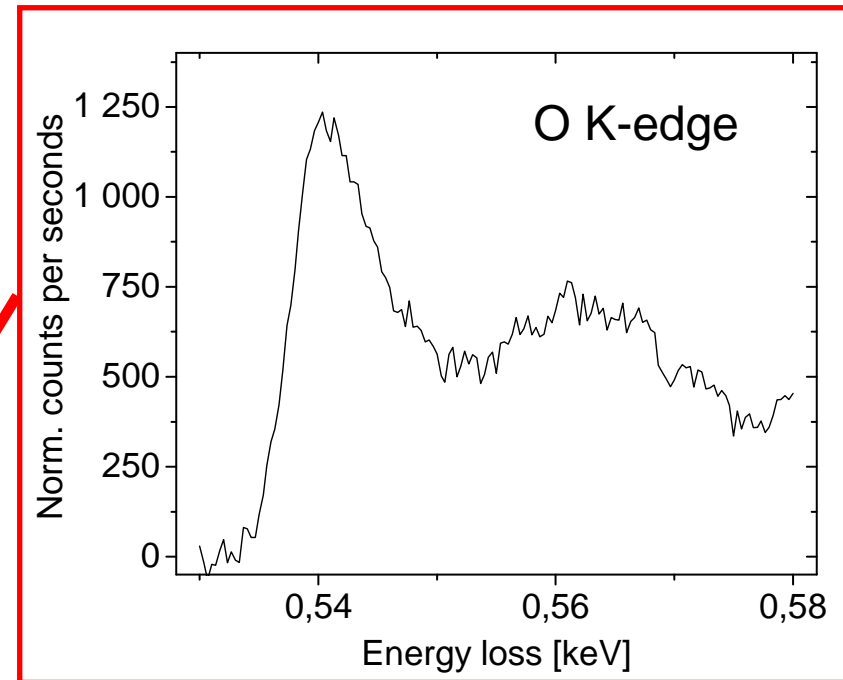
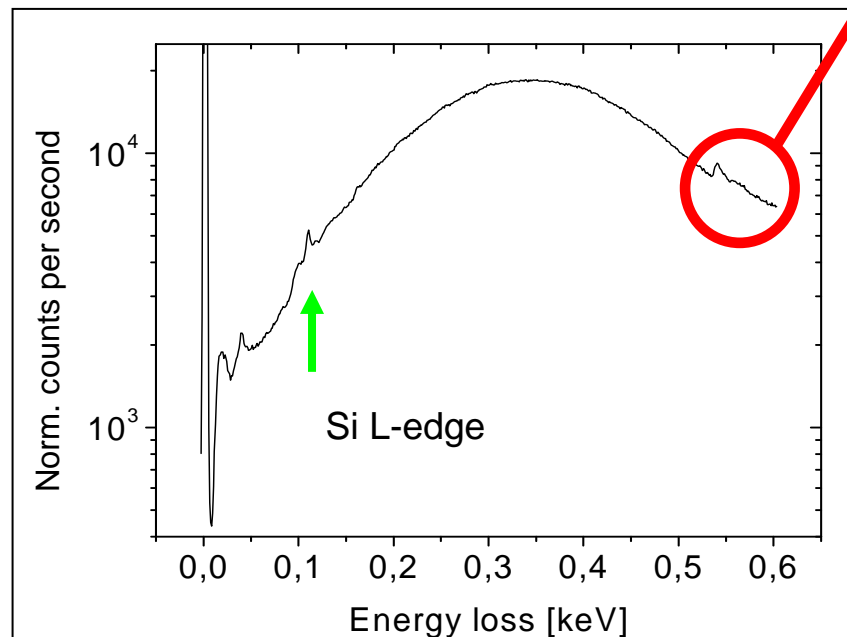
# X-ray Raman scattering - III

pyrolytic graphite (1 mm)  
carbon K-edge: 284 eV  
 $Q = 50 \text{ nm}^{-1}$



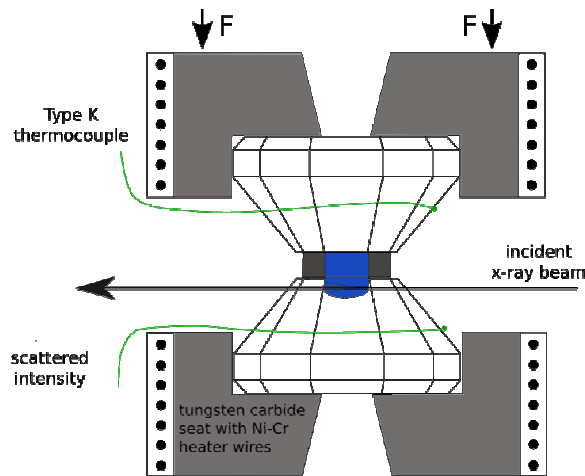
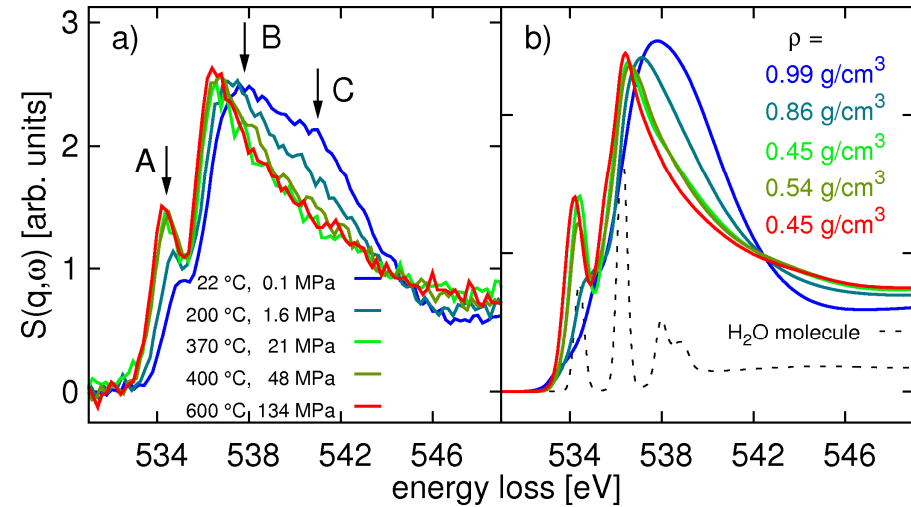
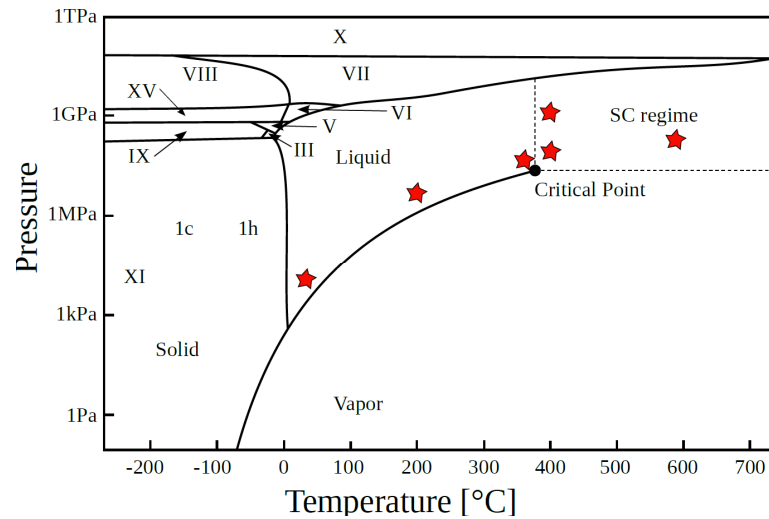
# X-ray Raman scattering - IV

borosilicate glass (130  $\mu\text{m}$ )  
oxygen K-edge: 540 eV  
 $Q = 97 \text{ nm}^{-1}$

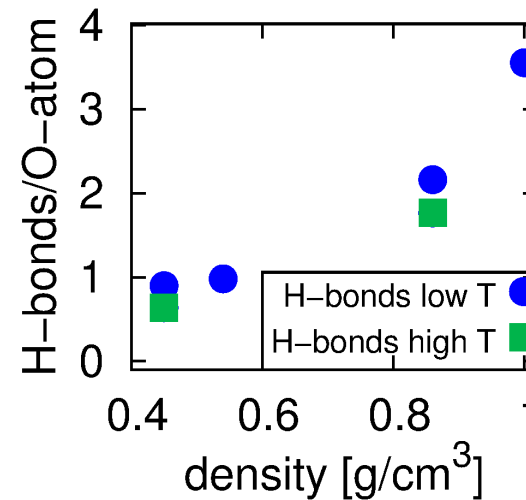


# X-ray Raman scattering – Example 1

## Microscopic structure of water at elevated P and T

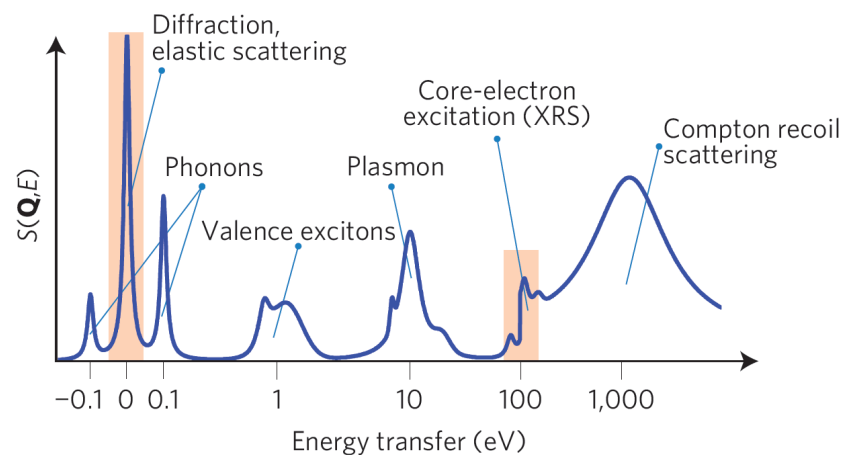
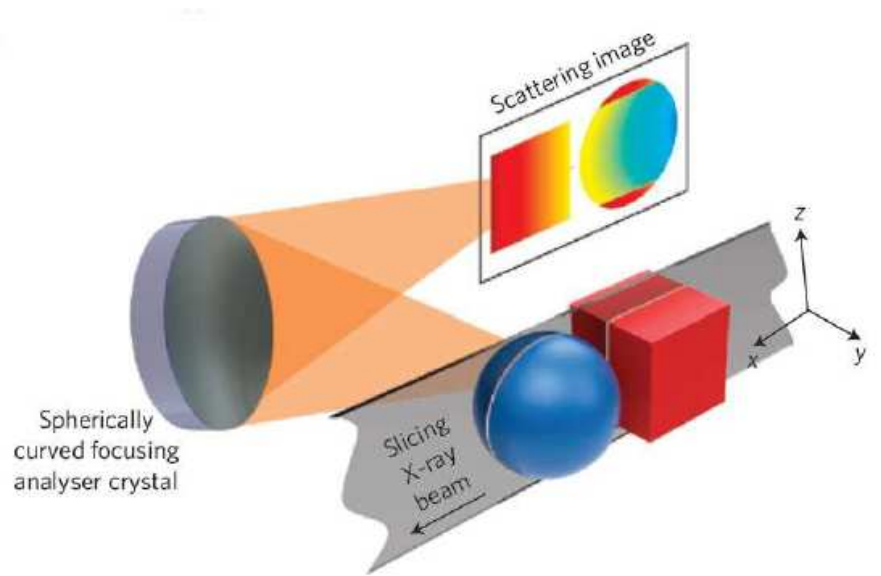


Resistively heated diamond anvil cell

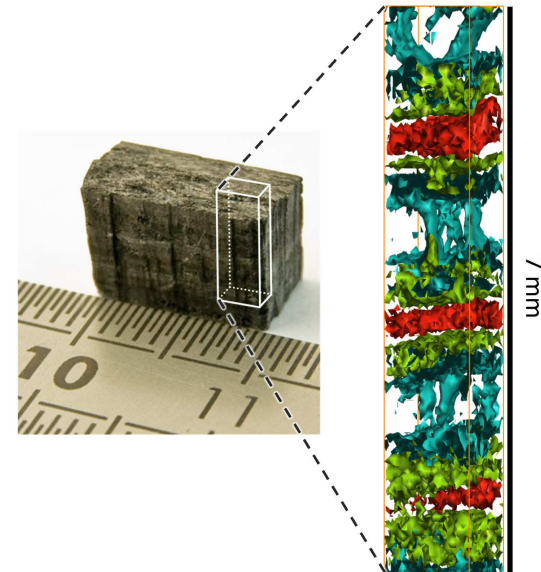


# X-ray Raman scattering – Example 2

## Direct tomography with chemical-bond contrast



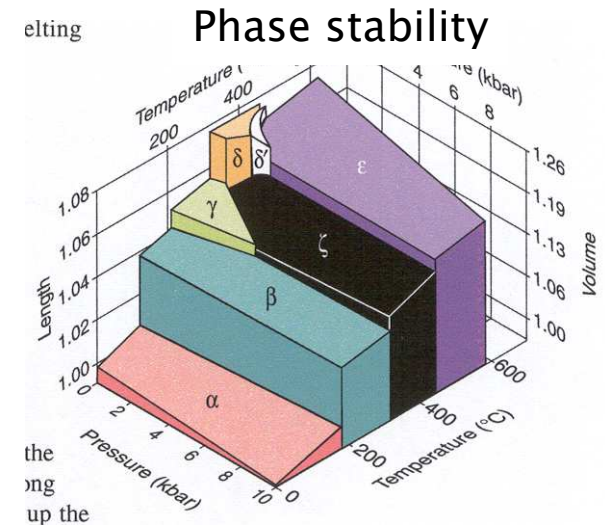
Sample of carbon fibre-reinforced silicon carbide



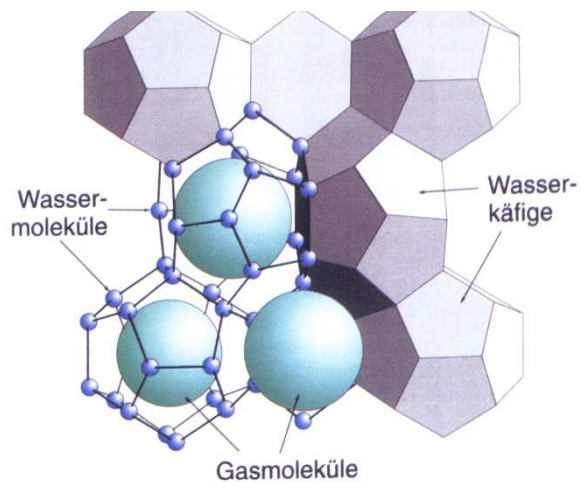
3D map of the  $sp^2$  chemical bonds (different colors represent different carbon bond orientations).

# IXS from phonons - I

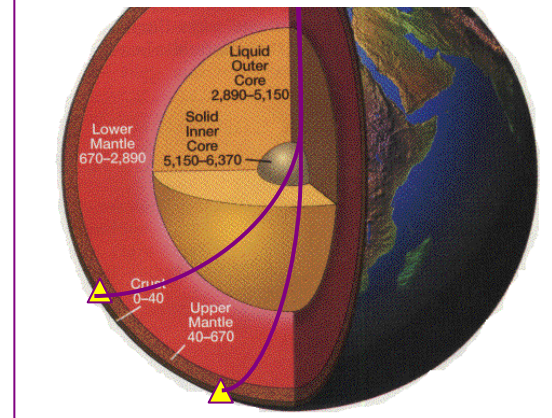
## Relevance of phonons



### Thermal Conductivity



### Sound velocities and elasticity



# IXS from phonons - II

## Vibrational spectroscopy: a short history

### Infrared absorption - 1881

W. Abney and E. Festing, R. Phil. Trans. Roy. Soc. 172, 887 (1881)

### Brillouin light scattering - 1922

L. Brillouin, Ann. Phys. (Paris) 17, 88 (1922)

### Raman scattering – 1928

C. V. Raman and K. S. Krishnan, Nature 121, 501 (1928)

### TDS: Phonon dispersion in Al – 1948

P. Olmer, Acta Cryst. 1 (1948) 57

### INS: Phonon dispersion in Al – 1955

B.N. Brockhouse and A.T. Stewart, Phys. Rev. 100, 756 (1955)

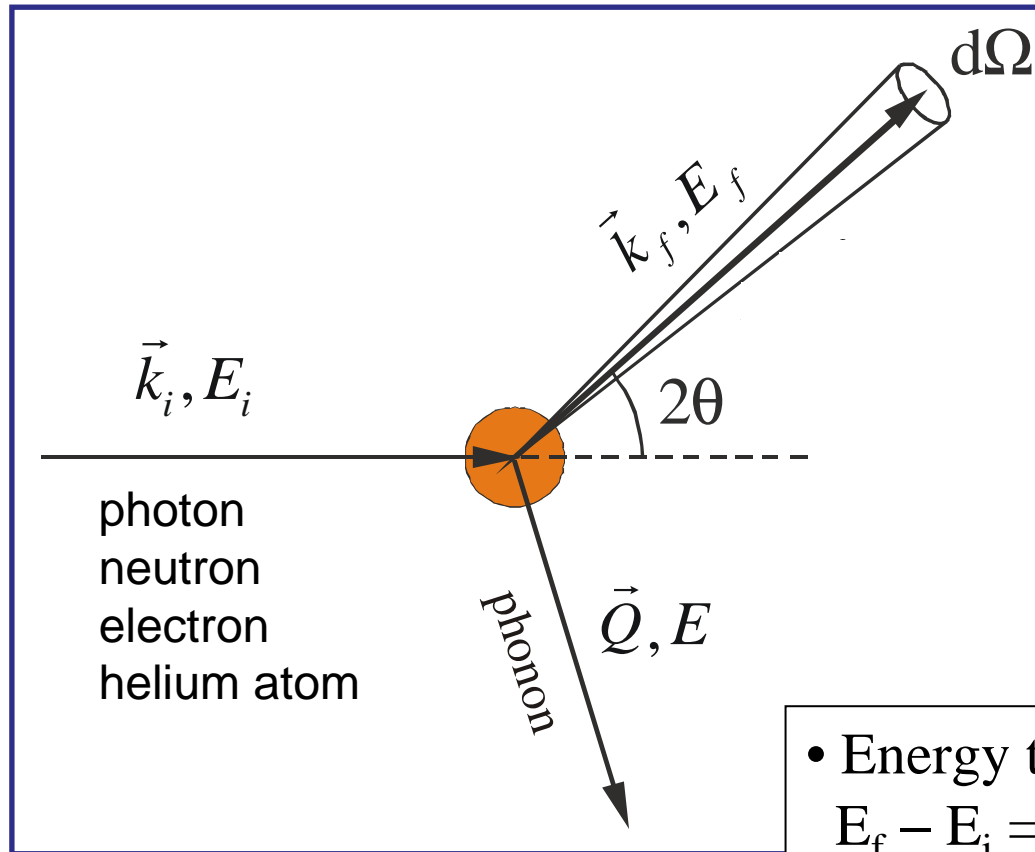
### IXS: Phonon dispersion in Be – 1987

B. Dorner, E. Burkel, Th. Illini and J. Peisl, Z. Phys. B – Cond. Matt. 69, 179 (1987)

### NIS: Phonon DOS in Fe – 1995

M. Seto, Y. Yoda, S. Kikuta, X.W. Zhang and M. Ando, Phys. Rev. Lett. 74, 3828 (1995)

# IXS from phonons - III



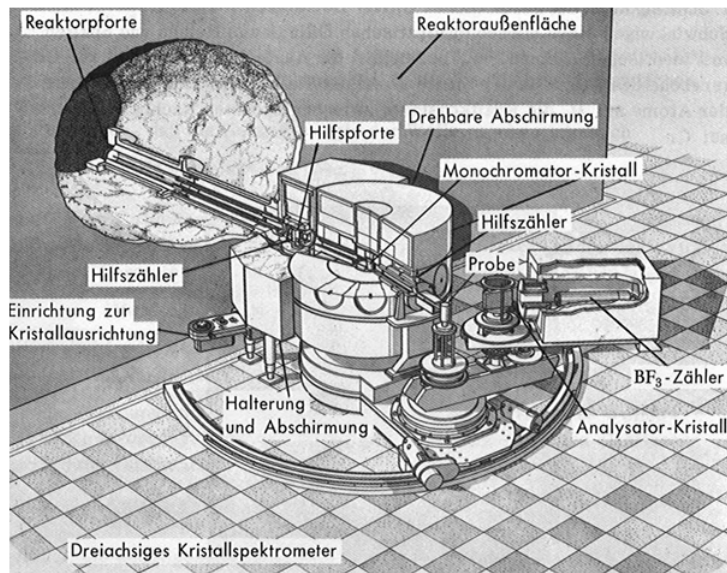
- Energy transfer:

$$E_f - E_i = E \quad (0.001 - 1 \text{ eV})$$

- Momentum transfer:

$$\vec{k}_f - \vec{k}_i = \vec{Q} \quad (0.0001 - 100 \text{ nm}^{-1})$$

# IXS from phonons - IV



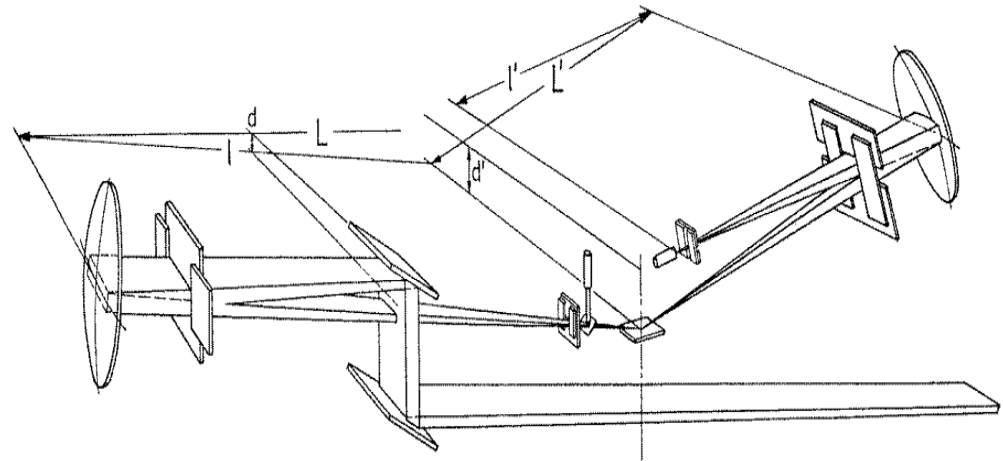
**Brockhouse (1955)**

**Thermal neutrons:**

$$E_i = 25 \text{ meV}$$

$$k_i = 38.5 \text{ nm}^{-1}$$

$$\Delta E/E = 0.01 - 0.1$$



The instrument INELAX at the HARWI wiggler line of HASYLAB.

**Burkel, Dorner and Peisl (1987)**

**Hard X-rays:**

$$E_i = 18 \text{ keV}$$

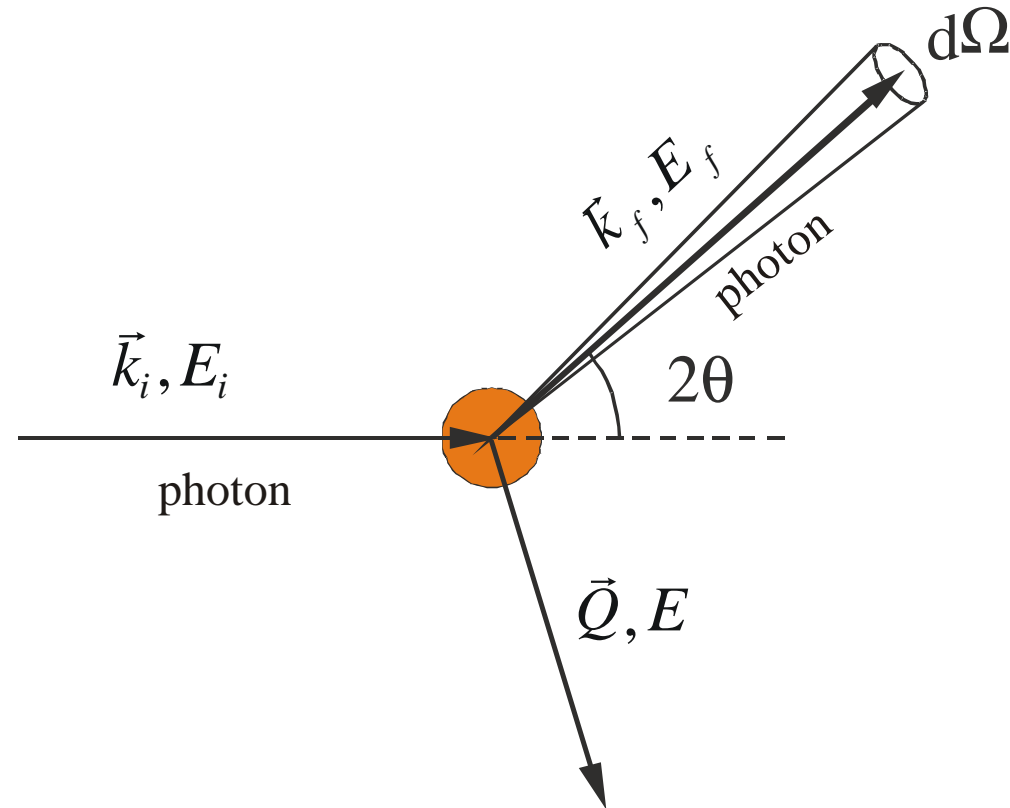
$$k_i = 91.2 \text{ nm}^{-1}$$

$$\Delta E/E \leq 1 \times 10^{-7}$$



# IXS from phonons - V

## IXS: Scattering kinematics

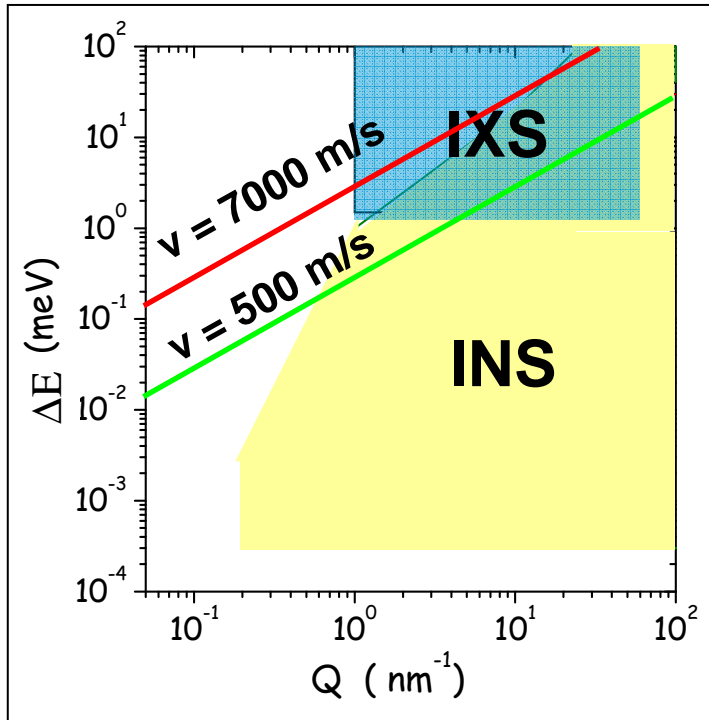


$$\begin{cases} E = E_i - E_f \\ |\vec{Q}| = 2|\vec{k}_i| \sin(\theta) \end{cases}$$

momentum transfer is defined only  
by scattering angle

# IXS from phonons - VI

No kinematic limitations:  $\Delta E$  independent of  $Q$



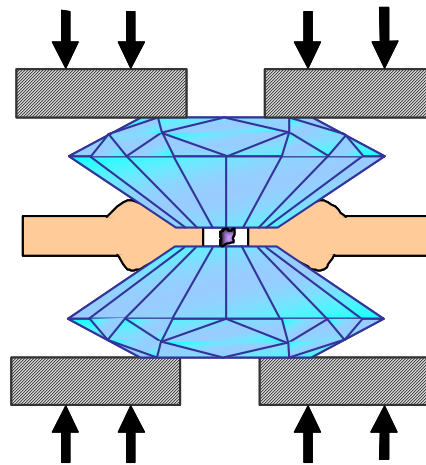
$$Q = 4\pi/\lambda \cdot \sin(\theta)$$
$$\Delta E = E_i - E_f$$

**Disordered systems:  
Explore new  $Q$ - $\Delta E$  range**

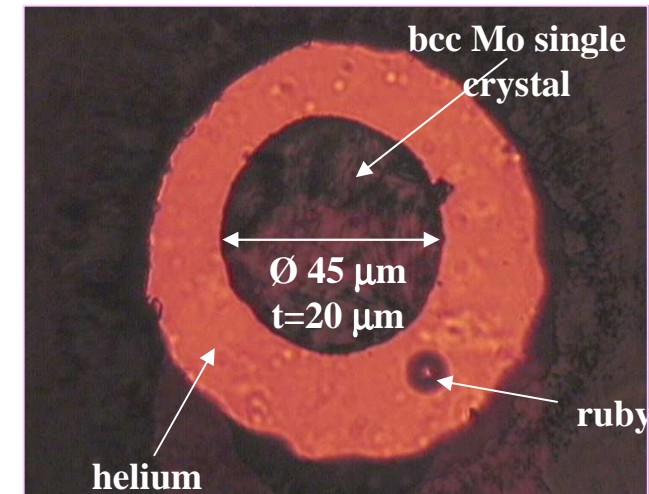
- Interplay between structure and dynamics on  $\approx$  nm length scale
- Relaxations on the picosecond time scale
- Excess of the VDOS (Boson peak)
- Nature of sound propagation and attenuation

# IXS from phonons - VII

Small sample volumes:  $10^{-4} - 10^{-5} \text{ mm}^3$



Diamond  
anvil cell



- (New) materials in very small quantities
- Very high pressures  $> 1\text{Mbar}$
- Study of surface phenomena

# IXS from phonons - VIII

**IXS**

$$\frac{\partial^2 \sigma}{\partial E \partial \Omega} = r_0^2 \frac{k_1}{k_2} (\vec{\epsilon}_1 \cdot \vec{\epsilon}_2) f(Q)^2 S(\vec{Q}, E)$$

- no correlation between momentum- and energy transfer
- $\Delta E/E = 10^{-7}$  to  $10^{-8}$
- Cross section  $\sim Z^2$  (for small Q)
- Cross section is dominated by photoelectric absorption ( $\sim \lambda^3 Z^4$ )
- no incoherent scattering
- small beams: 100  $\mu\text{m}$  or smaller

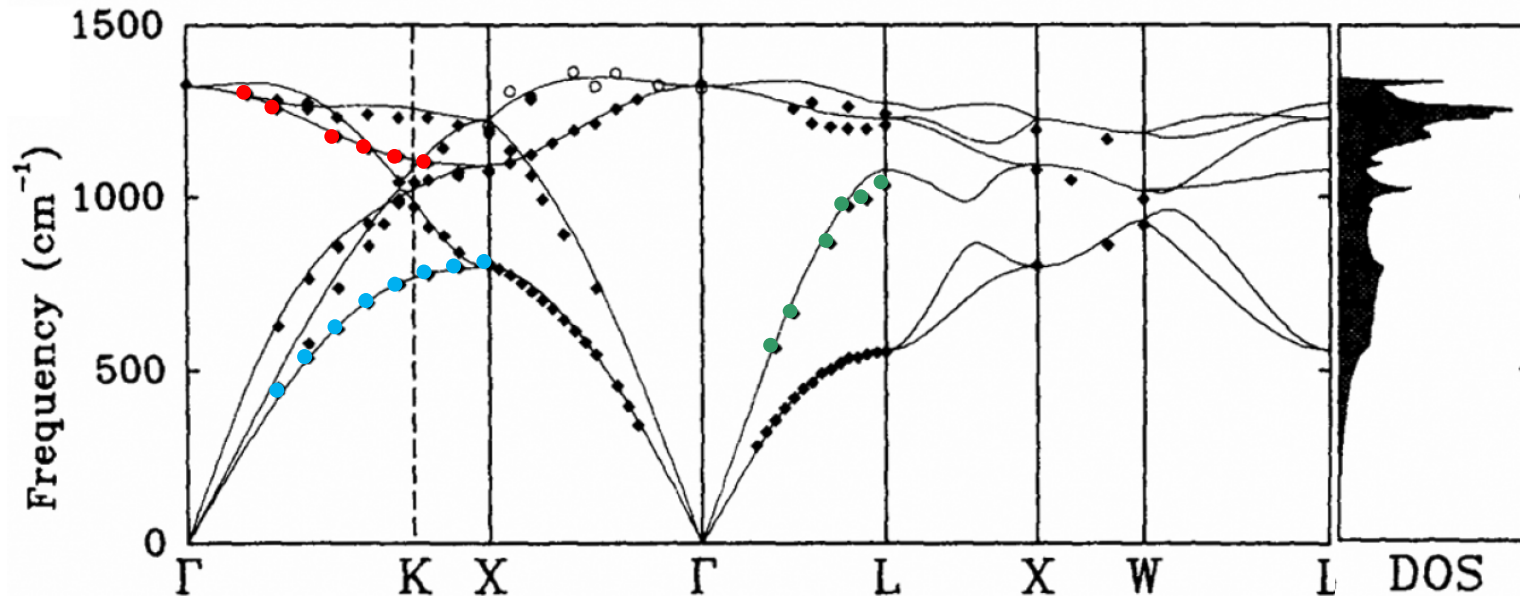
**INS**

$$\frac{\partial^2 \sigma}{\partial E \partial \Omega} = b^2 \frac{k_1}{k_2} S(\vec{Q}, E)$$

- strong correlation between momentum- and energy transfer
- $\Delta E/E = 10^{-1}$  to  $10^{-2}$
- Cross section  $\sim b^2$
- Weak absorption => multiple scattering
- incoherent scattering contributions
- large beams: several cm

# IXS from phonons - XI

## Phonon dispersion and phonon density of states



- single crystals

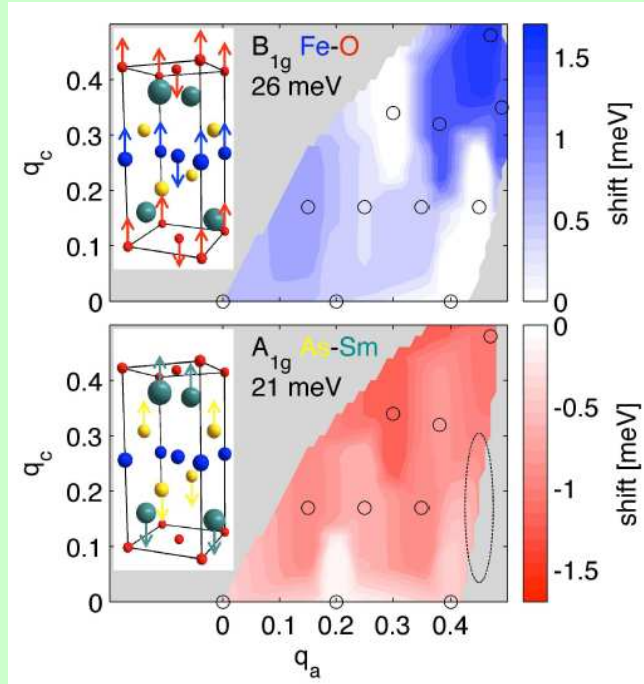
- triple axis: (very) time consuming
- time of flight: not available for X-rays

- polycrystalline materials

- reasonably time efficient
- limited information content

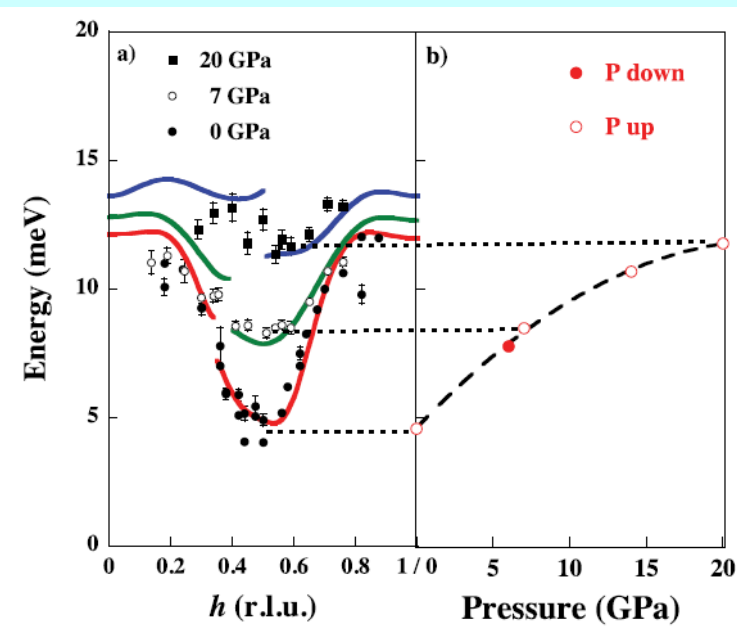
# IXS from phonons – correlated electron systems

## Doping dependence in $\text{SmFeAsO}_{1-x}\text{F}_y$



M. Le Tacon et al.; Phys. Rev. B 80, 220504

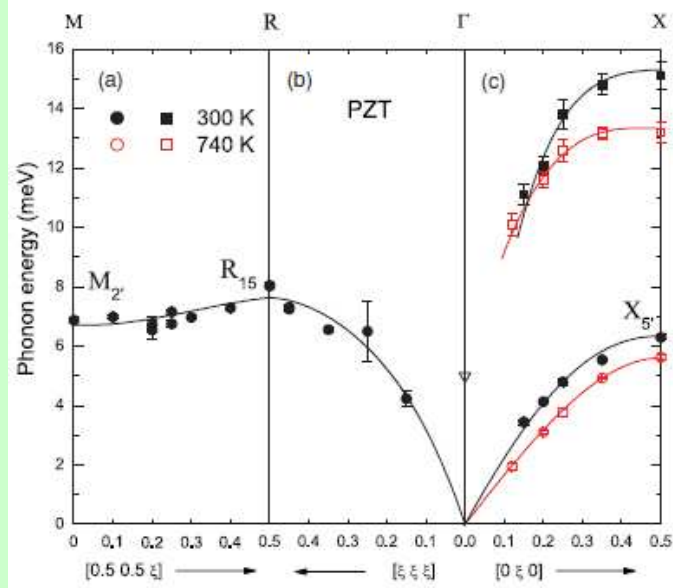
## e-ph coupling in $\alpha$ -U



S. Raymond et al.; PRL 107, 136401

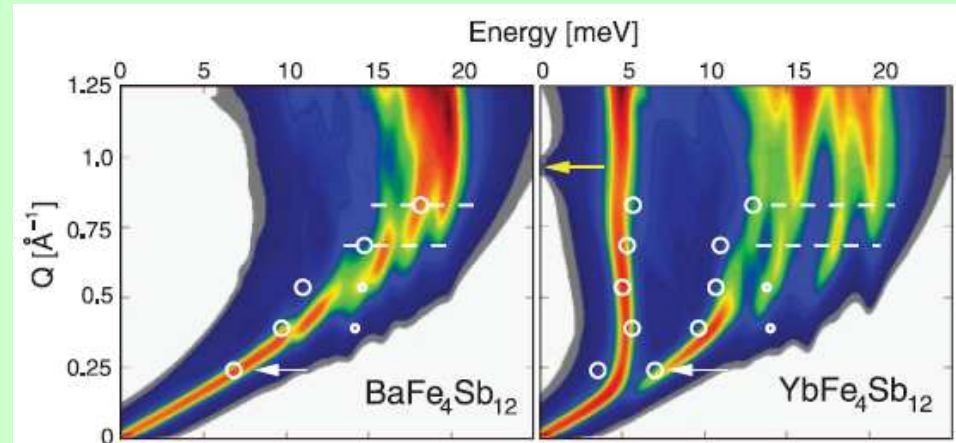
# IXS from phonons – functional materials

## Piezoelectrics $\text{PbZr}_{1-x}\text{Ti}_x\text{O}_3$



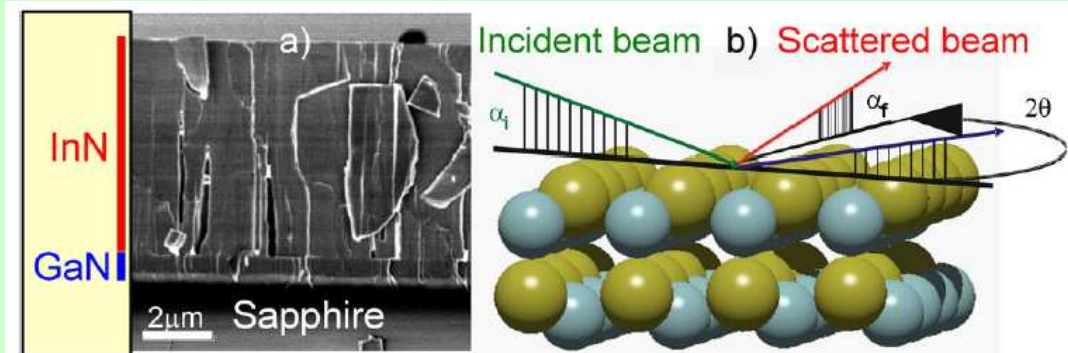
J. Hlinka et al.; PRB 83, 040101(R)

## Skutterudites



M.M. Koza et al.; PRB 84, 014306

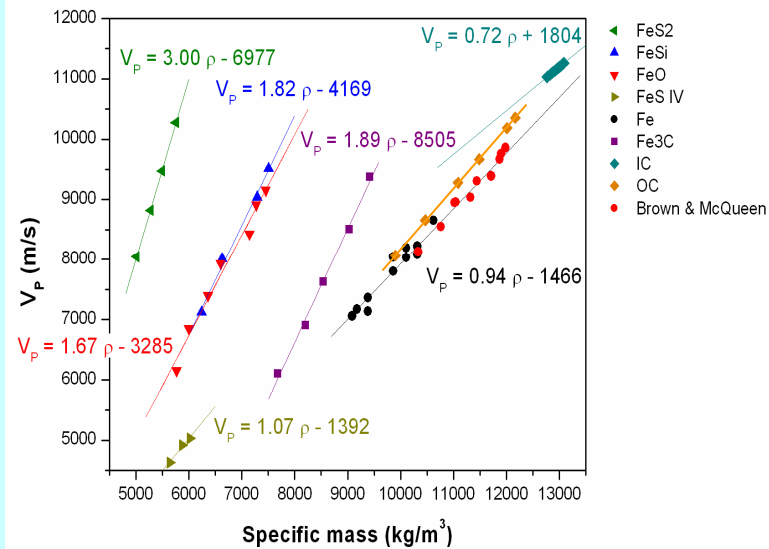
## InN thin film lattice dynamics



J. Serrano et al.; PRL 106, 205501

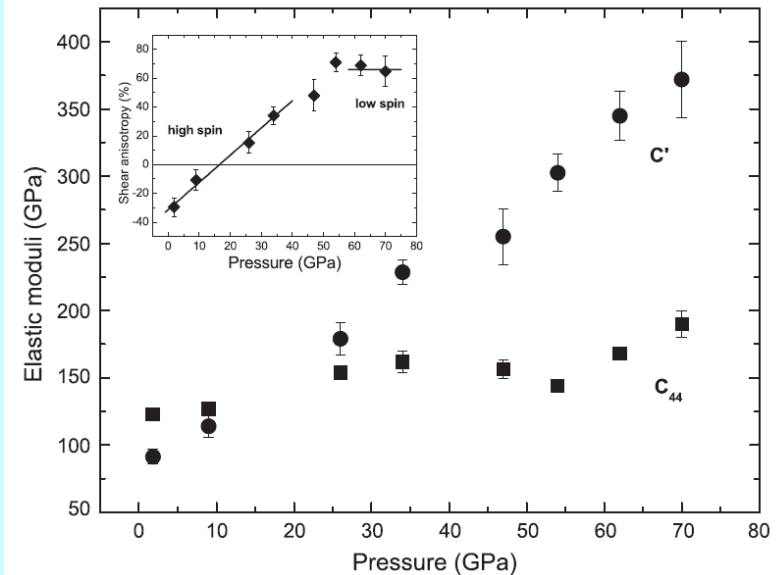
# IXS from phonons – Earth and planetary science

## Sound velocities in Earth's core



J. Badro et al.; Earth Plan. Science Lett. 98, 085501

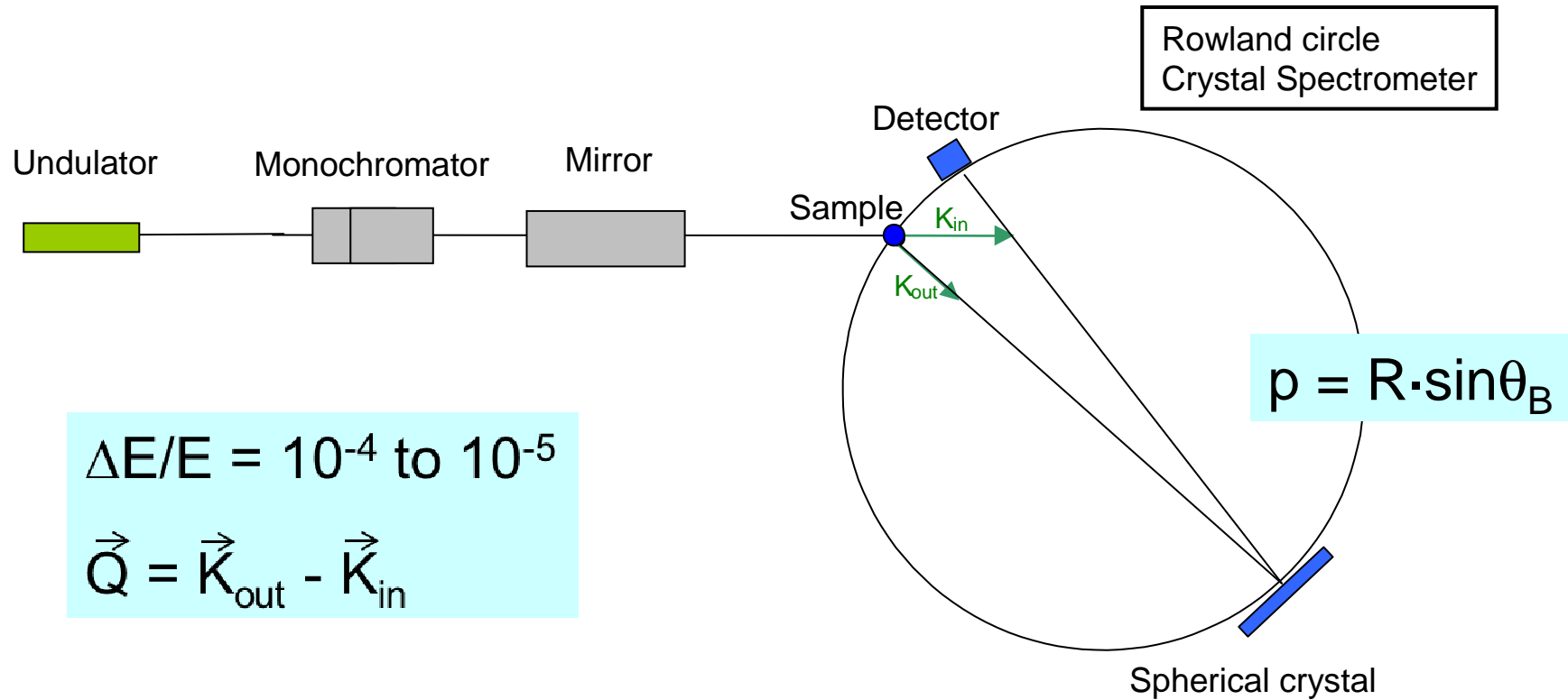
## Elastic anisotropy in $Mg_{83}Fe_{0.17}O$



D. Antonangeli et al.; Science 331, 64



# Instrumentation for IXS - I



$$\Delta E/E = 10^{-4} \text{ to } 10^{-5}$$

$$\vec{Q} = \vec{K}_{out} - \vec{K}_{in}$$

$$R = 1 \text{ or } 2 \text{ m}$$

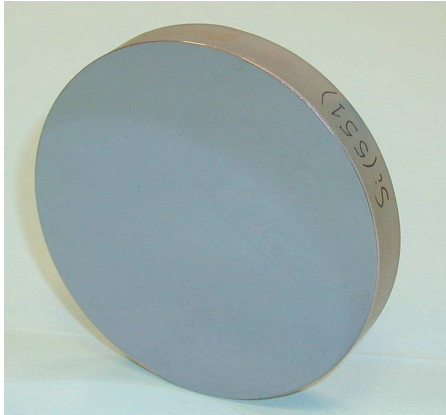
Si (Ge) (333, 440, 551, ...) crystals

Bragg angles  $\theta_B$ :  $65^\circ - 90^\circ$ .

$$\Delta E = 0.15 - 2 \text{ eV}$$

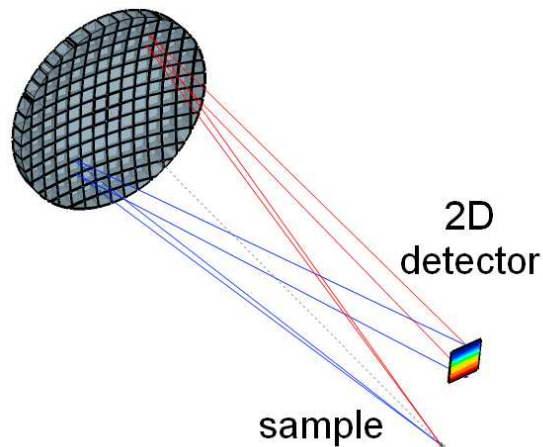
# Instrumentation for IXS - II

## Crystal analysers



### Anodic Bonded Elastically Bent Analyzers

medium energy resolution  
Very thin wafers (Si)  
Curvature radius 1 and 2 m  
Energy compensation algorithm



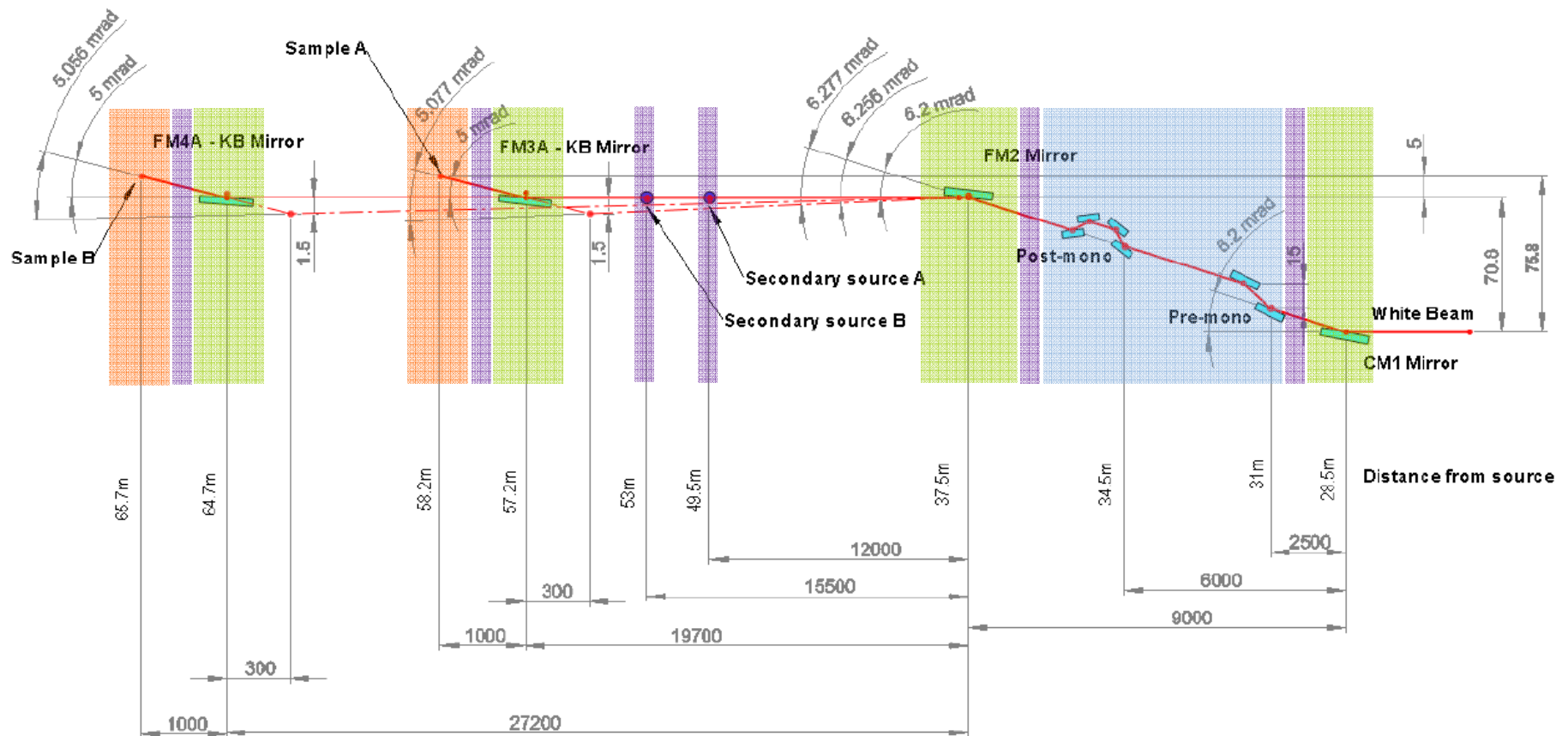
### Diced Analyzers

very high energy resolution  
cube size 0.8 mm x 0.8 mm x 3 mm  
Curvature radius 1, 2, 6.5 m  
Energy compensation algorithm

# Instrumentation for IXS - III

## ID20 @ ESRF

spectrometers monitoring monochromators focusing



lateral view

# Instrumentation for IXS - IV

## RIXS Spectrometer (ID20 - EH2)

Scan of both incident and scattered energy

**5 bent or diced analysers**

$\Delta E$  down to 25 meV

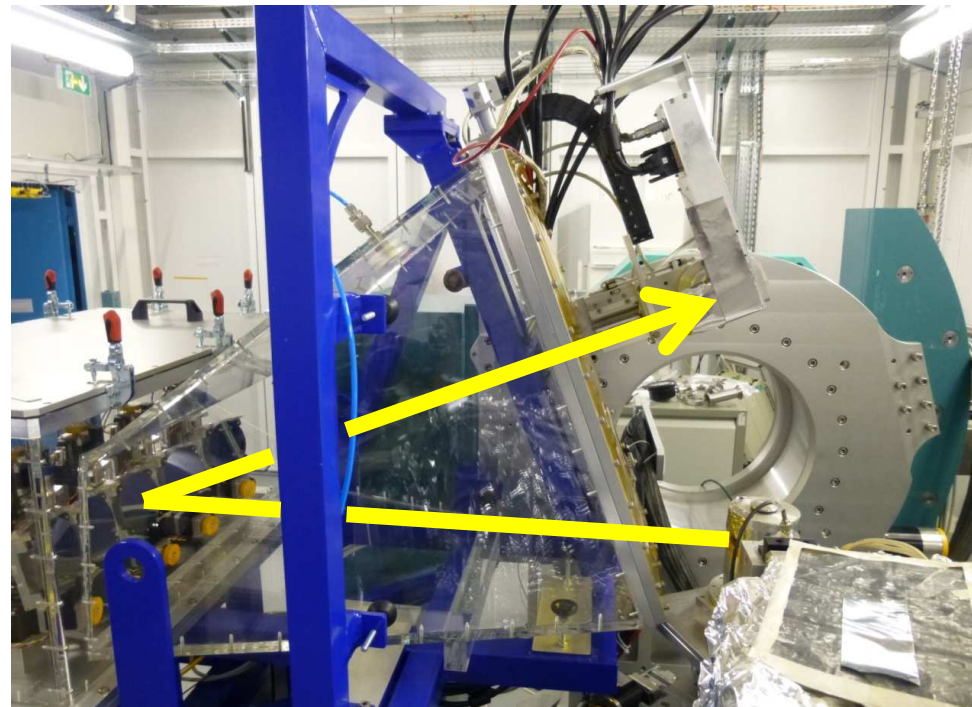
High flux and/or several  $q$ 's

**1x5 Maxipix Detectors**

55  $\mu\text{m}$  pixel size

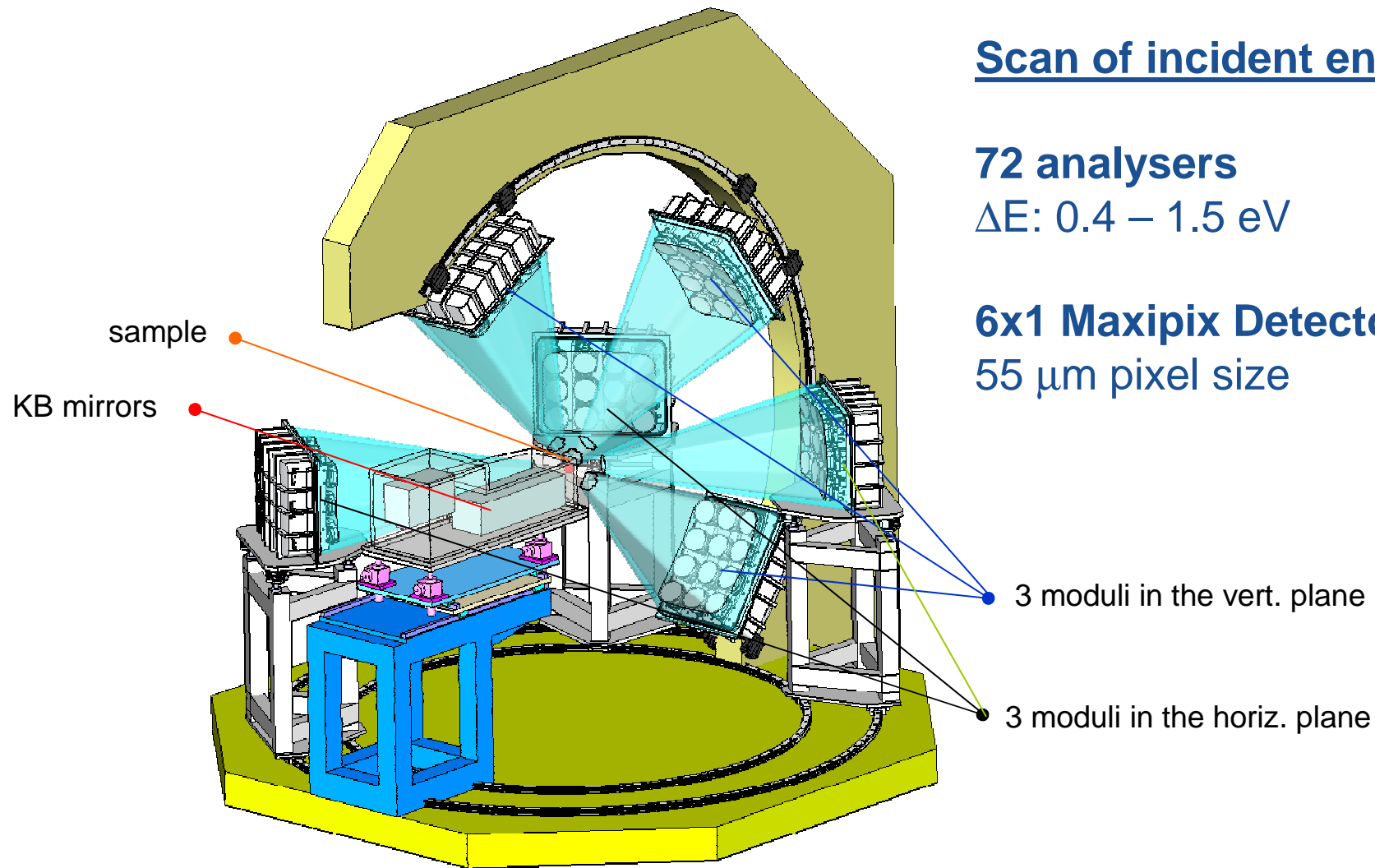
Energy compensation algorithm

Background removal



# Instrumentation for IXS - V

## X-ray Raman Spectrometer ID20 - EH3



Scan of incident energy

**72 analysers**

$\Delta E: 0.4 - 1.5 \text{ eV}$

**6x1 Maxipix Detectors**

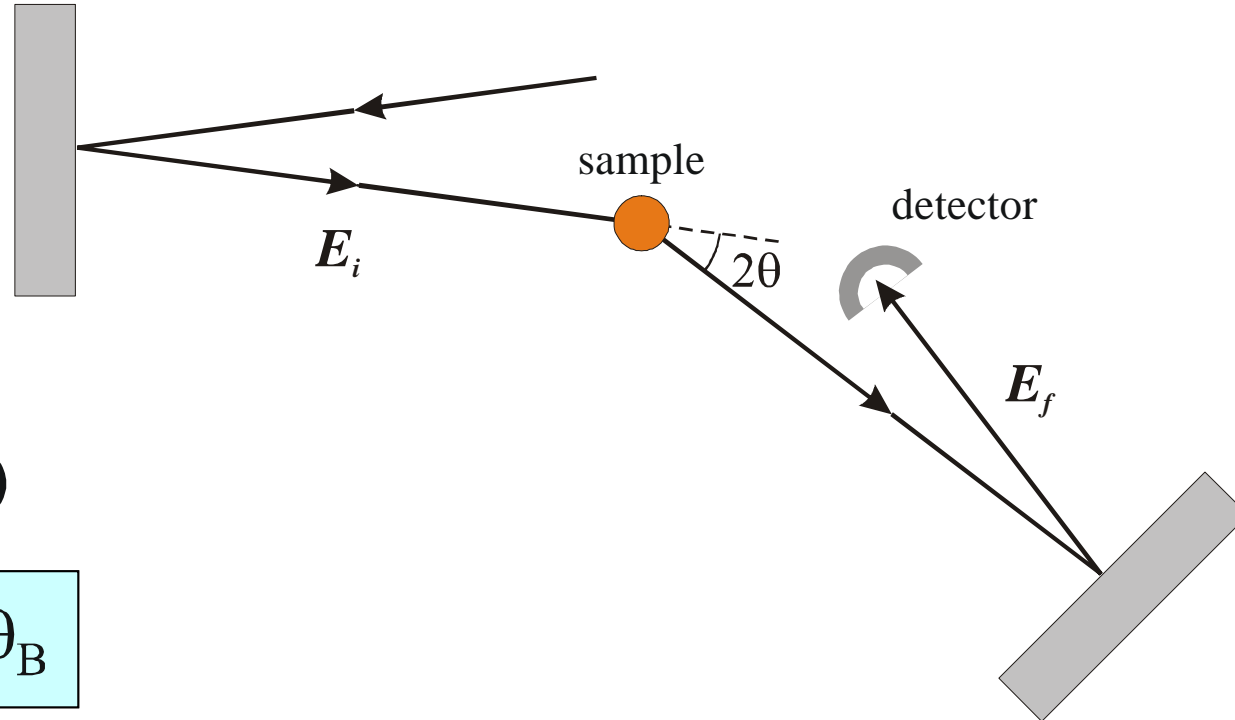
55  $\mu\text{m}$  pixel size

# Instrumentation for IXS - VI

## IXS set-up on ID28 at ESRF

### Monochromator:

Si(n,n,n),  $\theta_B = 89.98^\circ$   
n=7-13  
 $\lambda_1$  tunable



$$Q = 4\pi/\lambda \cdot \sin(\theta)$$

$$\lambda = 2 \cdot d(T) \sin\theta_B$$

$$\Delta d/d = \Delta E/E = -\alpha(T) \cdot \Delta T$$

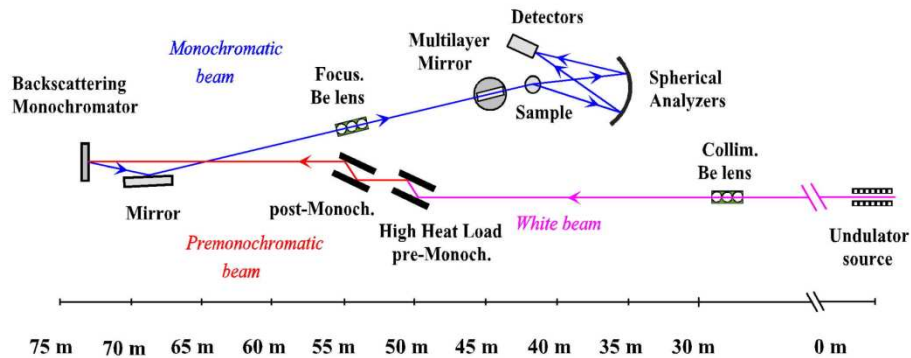
$\alpha = 2.58 \cdot 10^{-6} \text{ 1/K}$  at room temperature

### Analyser:

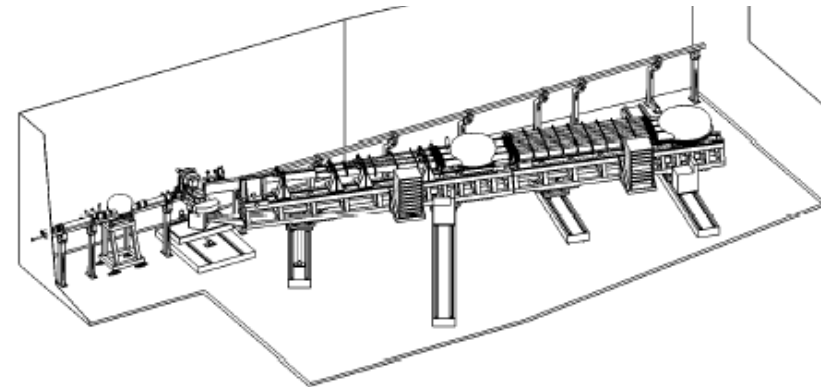
Si(n,n,n),  $\theta_B = 89.98^\circ$   
n=7-13  
 $\lambda_2$  constant

# Instrumentation for IXS - VII

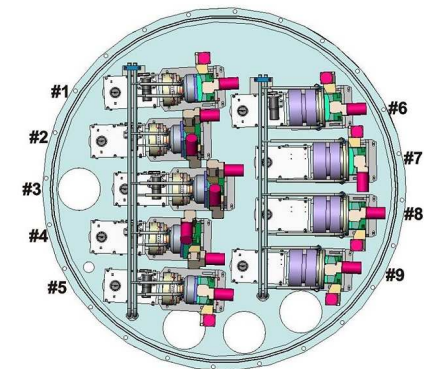
## ID28 @ ESRF



### 9- analyser crystal spectrometer



Reflection	$E_{inc}$ [keV]	$\Delta E$ [meV]	Q range [ $nm^{-1}$ ]
(8 8 8)	15.816	6	2 - 73
(9 9 9)	17.794	3.0	1.5 - 82
(12 12 12)	23.725	1.3	0.7 - 100



Spot size on sample:  $270 \times 60 \mu m^2 \rightarrow 14 \times 8 \mu m^2$  (H x V, FWHM)

## Further reading

- W. Schülke; *Electron dynamics by inelastic x-ray scattering*, Oxford University Press (2007)
- J.P. Rueff and A. Shukla; Rev. Mod. Physics 82, 847 (2010)  
*Inelastic x-ray scattering by electronic excitations under high pressure*
- L.J.P. Ament et al.; Rev. Mod. Physics 83, 705 (2011)  
*Resonant inelastic x-ray scattering studies of elementary excitations*
- M. Krisch and F. Sette; *Inelastic x-ray scattering from Phonons*, in Light Scattering in Solids, Novel Materials and Techniques, Topics in Applied Physics 108, Springer-Verlag (2007).
- A. Bosak, I. Fischer, and M. Krisch, in *Thermodynamic Properties of Solids. Experiment and Modeling*, Eds. S.L. Chaplot, R. Mittal, N. Choudhury. Wiley-VCH Weinheim, Germany (2010) 342 p. ISBN: 978-3-527-40812-2